

Notice of References Cited

Application/Control No.

10/578,717

Applicant(s)/Patent Under

Reexamination

HOLTMAN ET AL.

Examiner

HENOK G. HEYI

Art Unit

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0039470 A1	02-2003	Otsuka et al.	386/95
*	B	US-2006/0013088 A1	01-2006	Fontijn et al.	369/047.32
	C	US-			
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	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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